

<b>Notice of References Cited</b>	Application/Control No. 10/540,033	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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	U	English translation for JP 2001-40354 by computer, <a href="http://www4.ipdl.inpit.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=2001-040354">http://www4.ipdl.inpit.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=2001-040354</a>
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